

Australian Synchrotron

Thursday, 19 November 2020

Session 9 - Manufacturing, Engineering and Cultural Heritage (14:50 - 16:00)

time	[id] title	presenter
14:50	[288] Dual sample analysis on the XFM beamline: a new approach to increase the throughput of analysis of large samples	DOOLETTE, Casey
15:20	[215] Fast-scanning X-ray Diffraction Microscopy (SXDM) at the XFM beamline	Dr JONES, Michael
15:40	[221] Trace element distributions in Al-Zn based coating alloys on steel substrates investigated by synchrotron XFM	QU, Dongdong